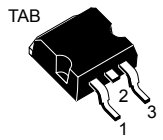
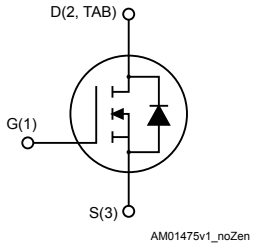
N-channel 300 V, 53 A, 0.037 Ω typ., MDmesh™ M5 Power MOSFET in a D²PAK package



D²PAK



Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STB45N30M5	300 V	0.040 Ω	53 A

- Extremely low $R_{DS(on)}$
- Low gate charge and input capacitance
- Excellent switching performance
- 100% avalanche tested

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET based on the MDmesh™ M5 innovative vertical process technology combined with the well-known PowerMESH™ horizontal layout. The resulting product offers extremely low on-resistance, making it particularly suitable for applications requiring high power and superior efficiency.

Product status link
STB45N30M5

Product summary	
Order code	STB45N30M5
Marking	45N30M5
Package	D²PAK
Packing	Tape and reel

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	±25	V
I_D	Drain current (continuous) at T_{case} = 25 °C	53	A
	Drain current (continuous) at T_{case} = 100 °C	34	
I_{DM}(1)	Drain current (pulsed)	212	A
P_{TOT}	Total dissipation at T_{case} = 25 °C	250	W
dv/dt(2)	Peak diode recovery voltage slope	15	V/ns
T_{stg}	Storage temperature range	-55 to 150	°C
T_j	Operating junction temperature range		

1. *Pulse width is limited by safe operating area.*
2. *I_{SD} ≤ 53 A, di/dt ≤ 400 A/µs, V_{DS} peak < $V_{(BR)DSS}$, V_{DD} = 240 V*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
$R_{thj\text{-}case}$	Thermal resistance junction-case	0.5	°C/W
$R_{thj\text{-}pcb}$(1)	Thermal resistance junction-pcb	30	

1. *When mounted on an 1-inch² FR-4, 2 Oz copper board.*

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or not repetitive (pulse width limited by T_j max)	16	A
E_{AS}	Single pulse avalanche energy (starting T_j = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	550	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified

Table 4. On-/off-states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS}= 0 V, I_D = 1 mA	300			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 300 V			1	µA
		V_{GS} = 0 V, V_{DS} = 300 V, T_C = 125 °C(1)			100	µA
I_{GSS}	Gate body leakage current	V_{DS} = 0 V, V_{GS} = ±25 V			±100	nA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	3	4	5	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 26.5 A		0.037	0.040	Ω

1. *Defined by design, not subject to production test.*

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	4240	-	pF
C_{oss}	Output capacitance		-	205	-	pF
C_{rss}	Reverse transfer capacitance		-	9.5	-	pF
$C_{o(tr)}$(1)	Time-related equivalent capacitance	V_{DS} = 0 to 240 V, V_{GS} = 0 V	-	373	-	pF
$C_{o(er)}$(2)	Energy-related equivalent capacitance		-	202	-	pF
R_G	Gate input resistance	f = 1 MHz, I_D = 0 A	-	1.4	-	Ω
Q_g	Total gate charge	V_{DD} = 240 V, I_D = 24 A, V_{GS} = 0 to 10 V (see Figure 15. Test circuit for gate charge behavior)	-	95	-	nC
Q_{gs}	Gate-source charge		-	23	-	nC
Q_{gd}	Gate-drain charge		-	37	-	nC

1. *$C_{o(tr)}$ is a constant capacitance value that gives the same charging time as Coss while V_{DS} is rising from 0 to 80% V_{DSS}.*
2. *$C_{o(er)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.*

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(v)}$	Voltage delay time	V_{DD} = 240 V, I_D = 32 A, R_G = 4.7 Ω, V_{GS} = 10 V (see Figure 16. Test circuit for inductive load switching and diode recovery times and Figure 19. Switching time waveform)	-	66	-	ns
$t_{r(v)}$	Voltage rise time		-	15	-	ns
$t_{f(i)}$	Current fall time		-	24	-	ns
$t_{c(off)}$	Crossing time		-	22.5	-	ns

Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		53	A
I_{SDM}(1)	Source-drain current (pulsed)		-		212	A
V_{SD}(2)	Forward on voltage	I_{SD} = 53 A, V_{GS} = 0 V	-		1.5	V
t_{rr}	Reverse recovery time	I_{SD} = 48 A, di/dt = 100 A/µs, V_{DD} = 60 V (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	223		ns
Q_{rr}	Reverse recovery charge		-	2.5		µC
I_{RRM}	Reverse recovery current		-	23		A
t_{rr}	Reverse recovery time	I_{SD} = 48 A, di/dt = 100 A/µs, V_{DD} = 60 V, T_j = 150 °C (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	280		ns
Q_{rr}	Reverse recovery charge		-	3.9		µC
I_{RRM}	Reverse recovery current		-	28		A

1. *Pulse width limited by safe operating area*
2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%*

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

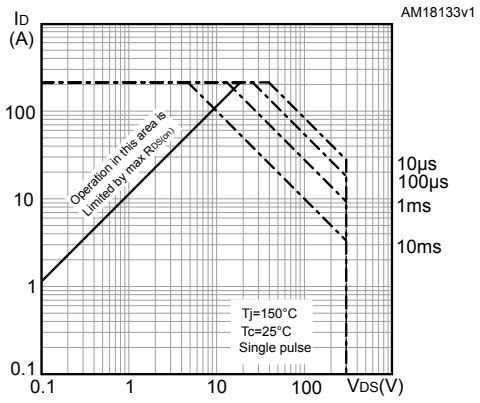


Figure 2. Thermal impedance

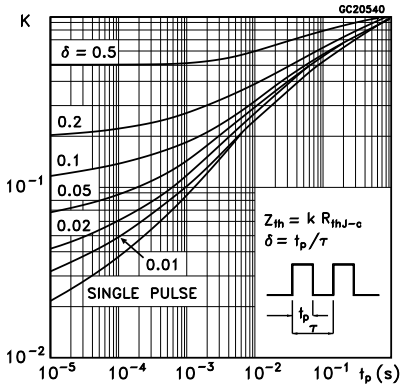


Figure 3. Output characteristics

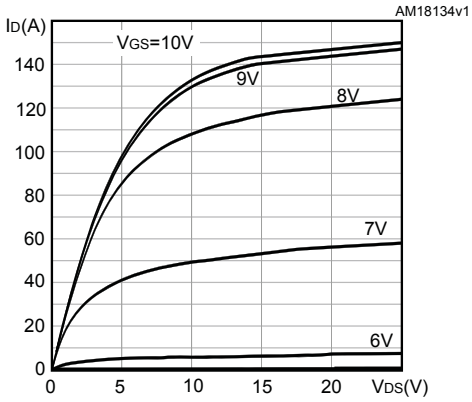


Figure 4. Transfer characteristics

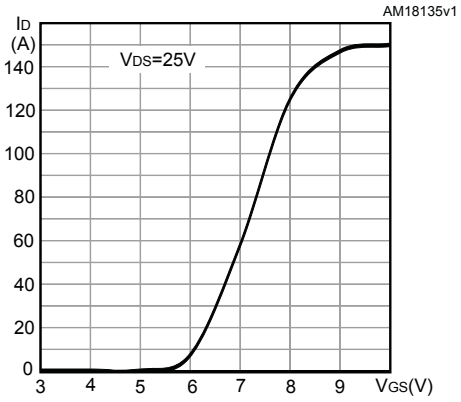


Figure 5. Gate charge vs gate-source voltage

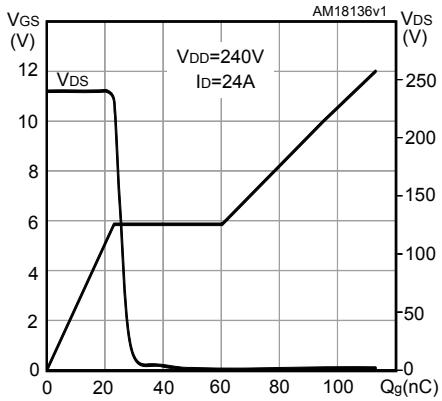


Figure 6. Static drain-source on-resistance

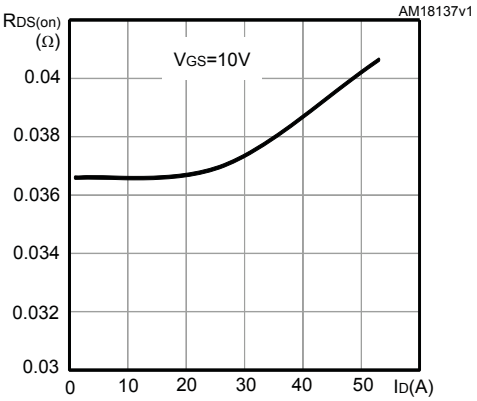


Figure 7. Capacitance variations

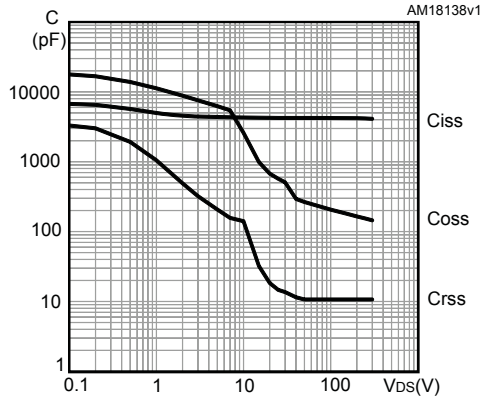


Figure 8. Output capacitance stored energy

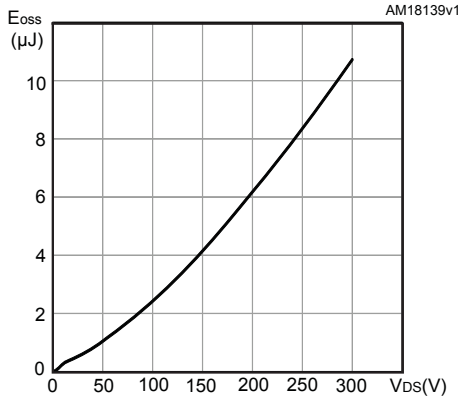


Figure 9. Normalized gate threshold voltage vs temperature

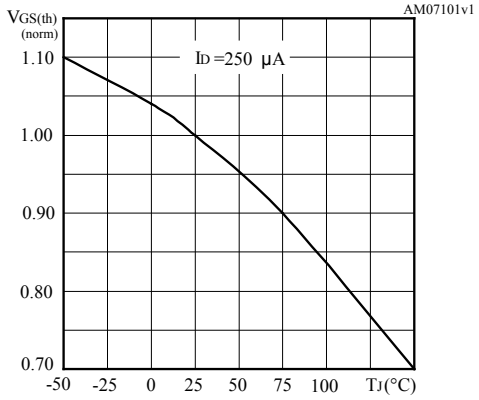


Figure 10. Normalized on-resistance vs temperature

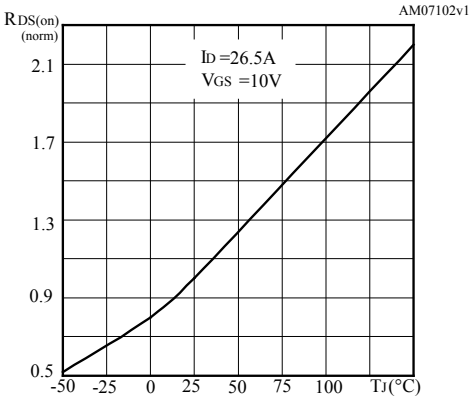


Figure 11. Normalized $V_{(BR)DSS}$ vs temperature

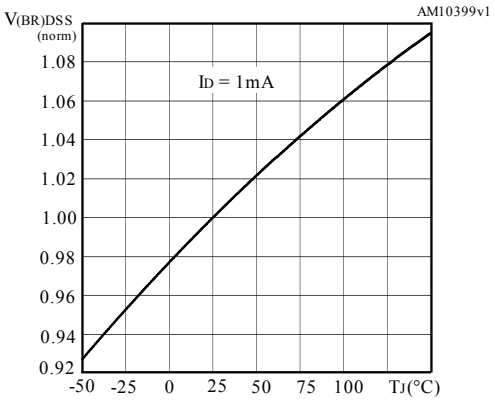


Figure 12. Source-drain diode forward characteristics

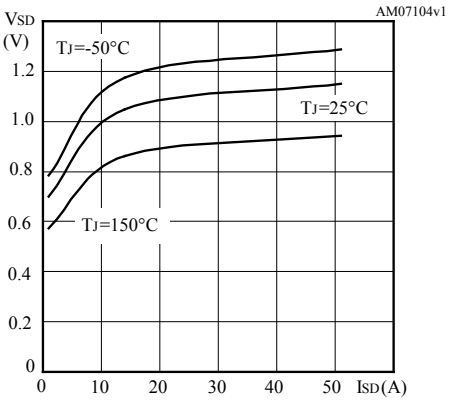
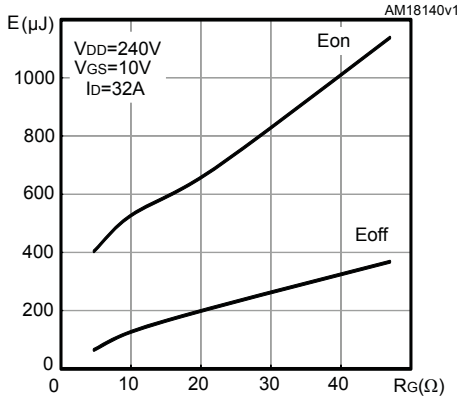


Figure 13. **Switching energy vs gate resistance**



3 Test circuits

Figure 14. Test circuit for resistive load switching times

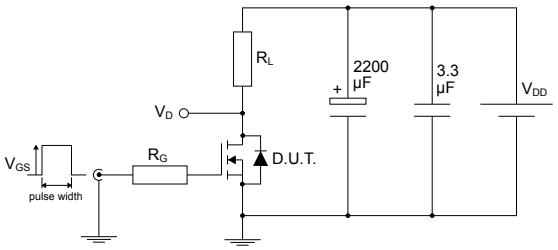


Figure 15. Test circuit for gate charge behavior

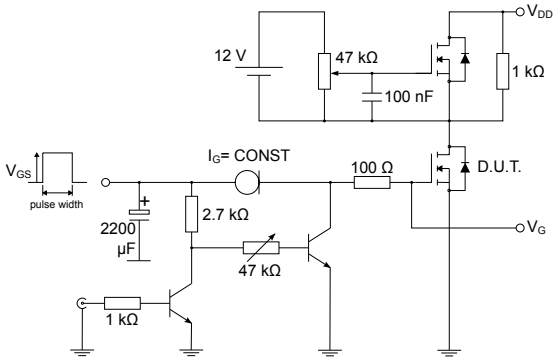


Figure 16. Test circuit for inductive load switching and diode recovery times

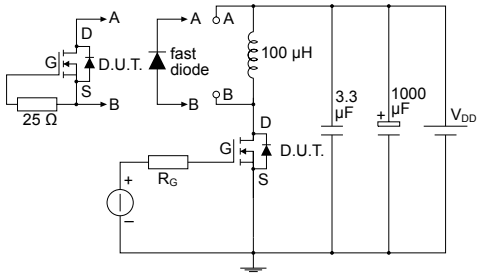


Figure 17. Unclamped inductive load test circuit

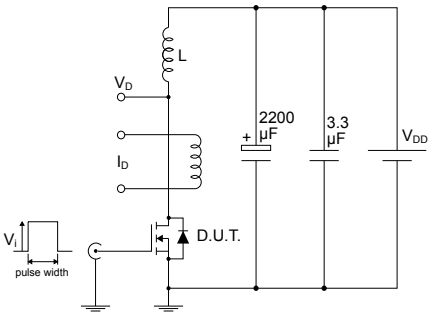


Figure 18. Unclamped inductive waveform

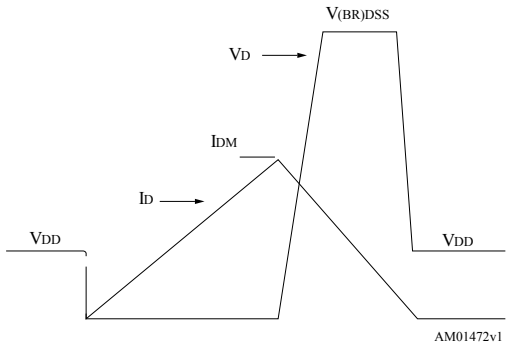
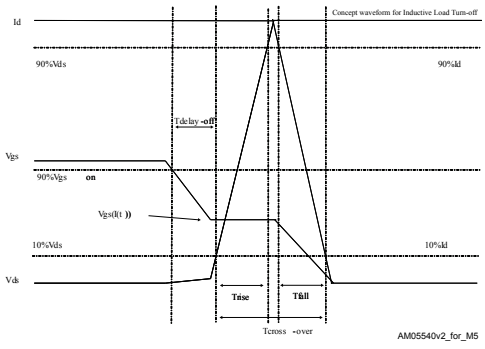


Figure 19. Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK® is an ST trademark.

4.1 D²PAK (TO-263) type A2 package information

Figure 20. D²PAK (TO-263) type A2 package outline

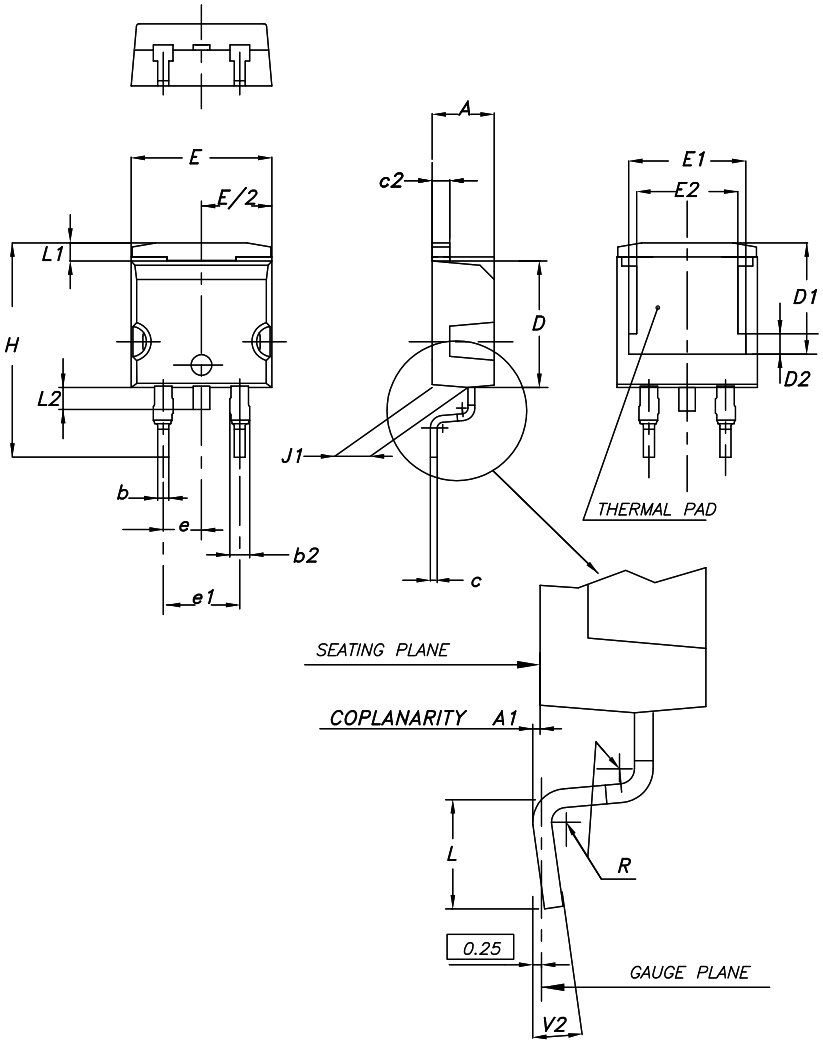


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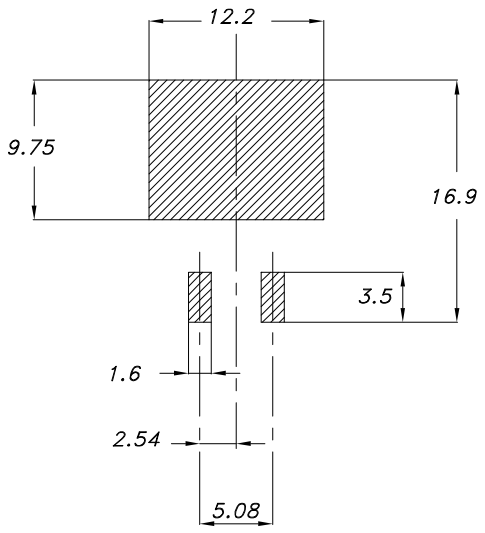
Table 8. D²PAK (TO-263) type A2 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
A1	0.03		0.23
b	0.70		0.93
b2	1.14		1.70
c	0.45		0.60
c2	1.23		1.36
D	8.95		9.35
D1	7.50	7.75	8.00
D2	1.10	1.30	1.50
E	10.00		10.40
E1	8.70	8.90	9.10
E2	7.30	7.50	7.70
e		2.54	
e1	4.88		5.28
H	15.00		15.85
J1	2.49		2.69
L	2.29		2.79
L1	1.27		1.40
L2	1.30		1.75
R		0.40	
V2	0°		8°

Figure 21. D²PAK (TO-263) recommended footprint (dimensions are in mm)



Footprint

4.2 D²PAK packing information

Figure 22. D²PAK tape outline

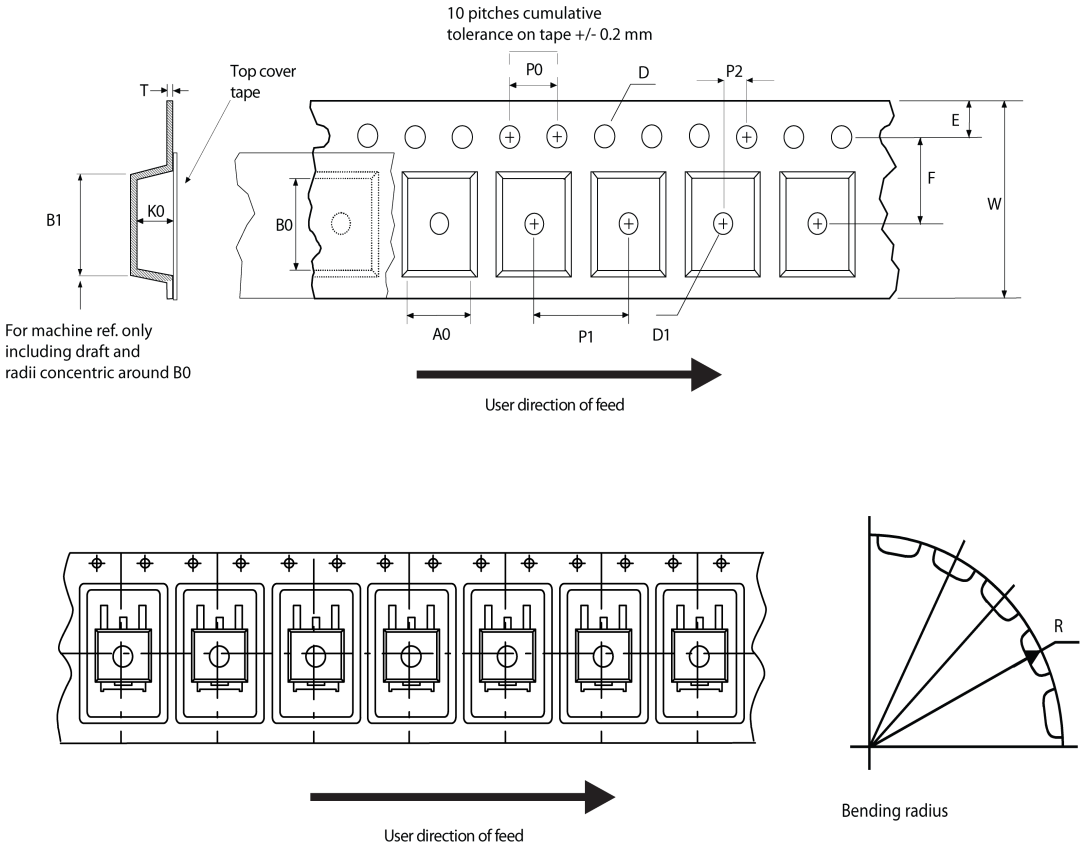


Figure 23. **D²PAK reel outline**

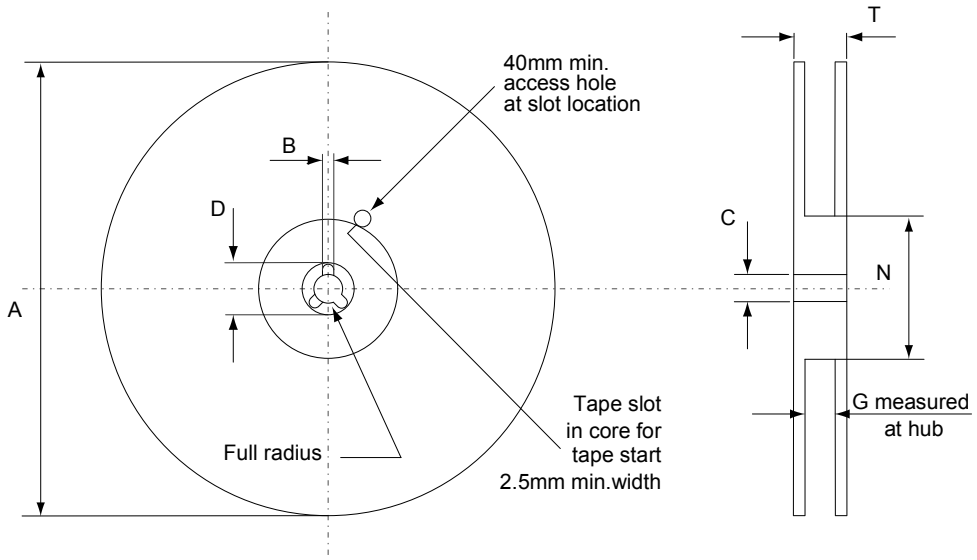


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Table 9. **D²PAK tape and reel mechanical data**

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	10.5	10.7	A		330
B0	15.7	15.9	B	1.5	
D	1.5	1.6	C	12.8	13.2
D1	1.59	1.61	D	20.2	
E	1.65	1.85	G	24.4	26.4
F	11.4	11.6	N	100	
K0	4.8	5.0	T		30.4
P0	3.9	4.1			
P1	11.9	12.1	Base quantity		1000
P2	1.9	2.1	Bulk quantity		1000
R	50				
T	0.25	0.35			
W	23.7	24.3			

Revision history

Table 10. **Document revision history**

Date	Version	Changes
16-May-2018	1	Initial release

Contents